

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/603,050 | Applicant(s)/Patent Under Reexamination MA ET AL. | |
| | Examiner Andrew Schechter | Art Unit 2871 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-2003/0043336 | 03-2003 | Sasaki et al. | 349/187 |
| | B | US-6,342,935 | 01-2002 | Jang et al. | 349/113 |
| | C | US-6,567,144 | 05-2003 | Kim et al. | 349/128 |
| | D | US-6,147,722 | 11-2000 | Shimada et al. | 349/43 |
| | E | US-6,344,888 | 02-2002 | Yasukawa, Masahiro | 349/113 |
| | F | US-6,512,561 | 01-2003 | Terashita et al. | 349/118 |
| | G | US-6,621,550 | 09-2003 | Arakawa et al. | 349/178 |
| | H | US-6,466,296 | 10-2002 | Yamada et al. | 349/160 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.